

Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/798,047	VANCE, JONATHAN
	Examiner	Art Unit
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
710	13	12/7/2006	CBS
709	220	12/7/2006	CBS
717	174	12/7/2006	CBS

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
PLUS	7/5/2006	CBS
PALM (DOUBLE PATENTING/INVENTOR)	7/5/2006	CBS
EAST (EPO, JPO, USPGPUB, USPAT, DERWENT, IBMTDB, USOCR)	7/5/2006	CBS
UPDATE -EAST	12/5/2006	CBS